

## Experiment - 7

Aim:- To determine the resistivity of semiconductor by four probe method.

Apparatus: probe arrangement, sample, own  
Required 0-2°C constant current generator, own power.

Theory:- At a constant temp. the resistance,  $R$  of a conductor is  $\propto$  to its length  $L$  and inversely  $\propto$  to its area of cross section  $A$ .

$$R = \frac{\rho L}{A} \quad \text{--- (i)}$$

Where  $\rho$  is resistivity of conductor and its unit is ohm meter. A semiconductor has electrical conductivity intermediate in magnitude b/w that of a conductor & insulator. Semiconductor differ from metal in their characteristics property of decreasing electrical resistivity with increasing temperature.



According to band theory the energy levels of semiconductor can be grouped into two bands, valance band & the conduction band.

In the presence of an external electric field it is electrons in valance band that can move freely thereby responsible for the electrical conductivity of semiconductor.

In case of intrinsic semiconductor the fermi level lies in b/w conduction band minimum & valance band maximum.

Since, conduction band lies above this fermi level at 0. When no thermal excitation are available to conduction is not possible at 0K.

As temperature increase the occupancy of conduction band goes up, thereby resulting in decrease of electrical resistivity of semiconductor.

$$\rho = \frac{\rho_0}{e^{\left(\frac{W}{kT}\right)}} \quad \text{--- (2)}$$



$F(w/s)$  is a deviation for computing resistivity which depends on value of  $w$  &  $S$ .

$$\rho_o = \frac{V}{I} \times 2 \pi S \quad \text{--- (3)}$$

where,  $V$  = potential difference

$I$  = current

$S$  = spacing b/w probes.

Applications:-

- ① Remote Sensing areas.
- ② Resistance thermometer.
- ③ Induction hardening process.
- ④ Accurate geometry factor estimation.
- ⑤ Characterization of fuel cells.  
bipolar plates.

Observation Table:-

Temperature	Voltage	Current	Resistivity
30	0.1693	6	6.0172
35	0.1644	6	5.8444
40	0.1599	6	5.6819
45	0.1556	6	5.5288
50	0.1515	6	5.3843
55	0.1477	6	5.2479
60	0.1440	6	5.1189
65	0.1406	6	4.9969
70	0.1376	6	4.8809
75	0.1342	6	4.7910
80	0.1313	6	4.6665

Calculations:-

Distance b/w probes  $S$  as 0.2 cm  
 & thickness of sample was  
 0.05 cm.

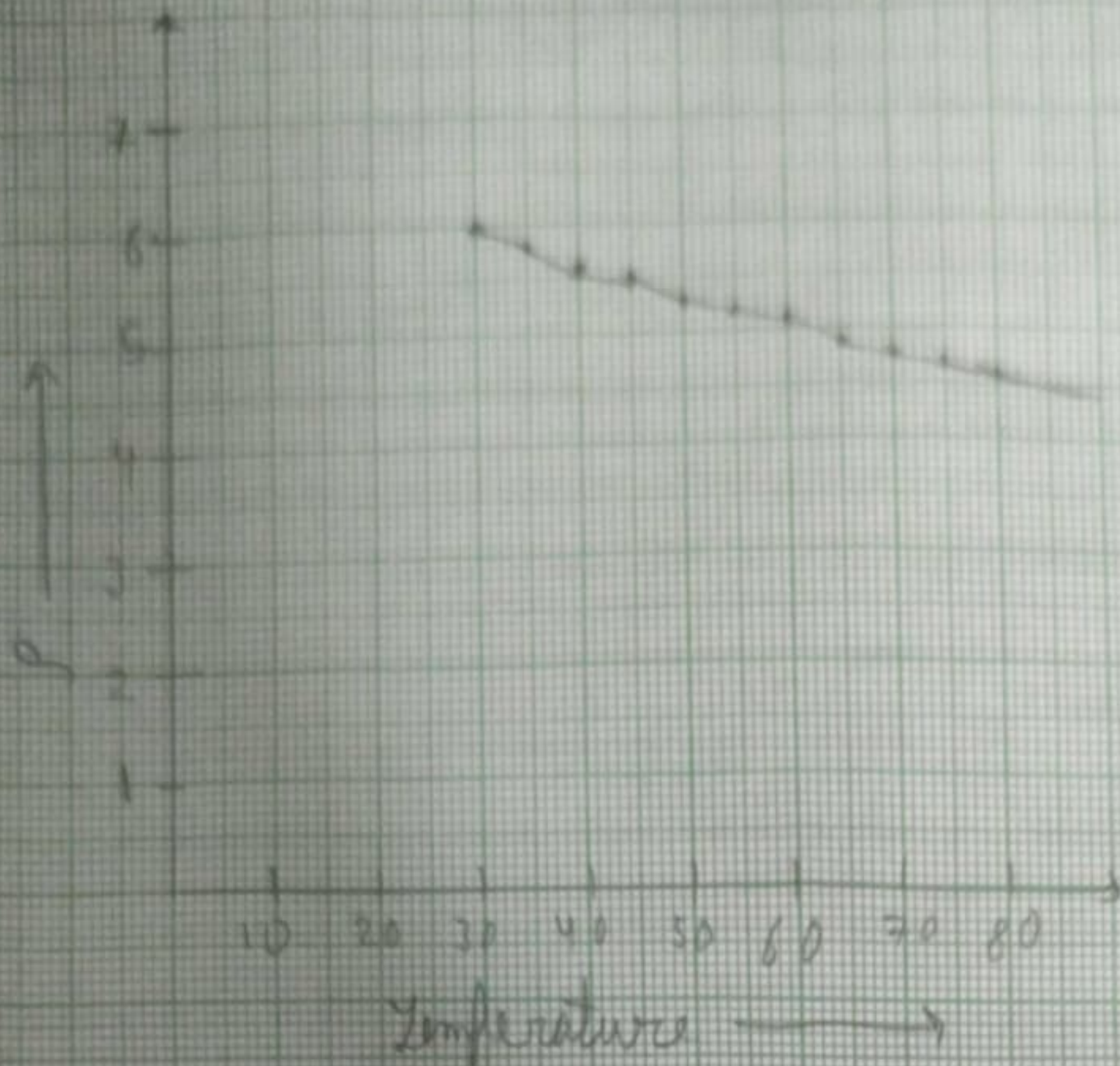
From Standard table  $F(w/s) = 5.89$

$$\rho_0 = \frac{V}{I} \times 2\pi S = \frac{0.1693}{6} \times 2 \times 3.14 \times 0.2$$

$$\rho_0 = 35.4$$



Y axis: 1 box = 1 unit  
X axis: 1 box = 10 units



$$\rho = \frac{\rho_0}{F(wls)} = \frac{35.4}{5.89} = 6.0172 \text{ ohm cm.}$$

Similarly for all

for  $T=80$

$$\rho_0 = \frac{V}{I} \times 2\pi S = \frac{0.1313}{6} \times 2 \times 3.14 \times 0.2$$

$$\rho_0 = 27.4$$

$$\rho = \frac{\rho_0}{F(wls)} = \frac{27.4}{5.89} = 4.6665 \text{ ohm cm}$$

Result:- The resistivity of given Semiconductor by your probe method = 5.2853 ohm cm

Note:- The resistivity written in result is the mean of resistivities of different temperature.